

**Search Notes**

Application/Control No.

10/650,661

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under  
Reexamination

MORIWAKI ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	285, first 300 patents	06/15/05	NKV
330	296, first 400 patents	11/18/04	NKV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See Search History Printout		11/05/05	NKV

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	11/05/05	NKV